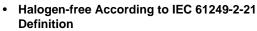


# AP9575AGI-HF-VB Datasheet P-Channel 60 V (D-S) MOSFET

PRODUCT	SUMMARY		
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ ) Max.	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)
- 60	$0.050 \text{ at V}_{GS} = -10 \text{ V}$	- 30	67
- 00	$0.060$ at $V_{GS} = -4.5 \text{ V}$	- 24	07

#### **FEATURES**

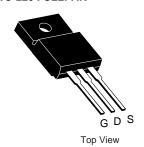


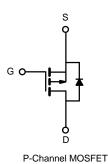


- TrenchFET® Power MOSFET
- 100 % R<sub>g</sub> and UIS Tested
- Compliant to RoHS Directive 2002/95/EC



#### **TO-220 FULLPAK**





<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)							
Parameter		Symbol	Limit	Unit			
Drain-Source Voltage		V <sub>DS</sub>	- 60	V			
Gate-Source Voltage	V <sub>GS</sub>	± 20	V				
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>C</sub> = 25 °C	1_	- 30	A			
Continuous Diam Current (1j = 150 °C)	T <sub>C</sub> = 70 °C	- I <sub>D</sub>	- 29				
Pulsed Drain Current (t = 300 μs)	I <sub>DM</sub>	- 100	^				
Avalanche Current	I <sub>AS</sub>	- 32					
Single Avalanche Energy <sup>a</sup>	L = 0.1 mH	E <sub>AS</sub>	51	mJ			
Maximum Power Dissipation <sup>a</sup>	T <sub>C</sub> = 25 °C	P <sub>D</sub>	41.7 <sup>b</sup>	W			
	T <sub>A</sub> = 25 °C <sup>c</sup>		2.1				
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C			

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Limit	Unit	
Junction-to-Ambient (PCB Mount) <sup>c</sup>	R <sub>thJA</sub>	60	°C/W	
Junction-to-Case (Drain)	R <sub>thJC</sub>	3	C/VV	

#### Notes:

- a. Duty cycle  $\leq$  1 %.
- b. See SOA curve for voltage derating.
- c. When mounted on 1" square PCB (FR-4 material).



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{DS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	- 60			V
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 2.5	
Gate-Body Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 250	nA
		V <sub>DS</sub> = - 60 V, V <sub>GS</sub> = 0 V			- 1	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 60 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C			- 50	μΑ
		V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 150 °C			- 250	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \le -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α
	D	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 14 A		0.050		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 12 A		0.060		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>DS</sub> = - 20 V, I <sub>D</sub> = - 14 A		40		S
Dynamic <sup>b</sup>						
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = - 20 V, f = 1 MHz		1765		pF
Output Capacitance	C <sub>oss</sub>			230		
Reverse Transfer Capacitance	C <sub>rss</sub>			180		
Total Gate Charge <sup>c</sup>	$Q_g$			67		nC
Gate-Source Charge <sup>c</sup>	Q <sub>gs</sub>	V <sub>DS</sub> = - 20 V, V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 14 A		13.5		
Gate-Drain Charge <sup>c</sup>	$Q_{gd}$			14		
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.5	2.5	5	Ω
Turn-On Delay Time <sup>c</sup>	t <sub>d(on)</sub>			10	20	
Rise Time <sup>c</sup>	t <sub>r</sub>	$V_{DD}$ = - 20 V, $R_L$ = 2 $\Omega$		11	20	no
Turn-Off Delay Time <sup>c</sup>	t <sub>d(off)</sub>	$I_{D} \cong -10 \text{ A}, V_{GEN} = -10 \text{ V}, R_{g} = 1 \Omega$		42	63	ns ns
Fall Time <sup>c</sup>	t <sub>f</sub>			12	20	
Drain-Source Body Diode Ratings ar	nd Characteri	stics T <sub>C</sub> = 25 °C <sup>b</sup>				
Continuous Current	Is				- 36	
Pulsed Current	I <sub>SM</sub>				- 100	Α
Forward Voltage <sup>a</sup>	V <sub>SD</sub>	I <sub>F</sub> = - 10 A, V <sub>GS</sub> = 0 V		- 0.8	- 1.5	V
Reverse Recovery Time	t <sub>rr</sub>			38	57	ns
Peak Reverse Recovery Current	I <sub>RM(REC)</sub>	I <sub>F</sub> = - 10 A, dI/dt = 100 A/μs		2.3	3.5	Α
Reverse Recovery Charge	Q <sub>rr</sub>	1		40	60	nC

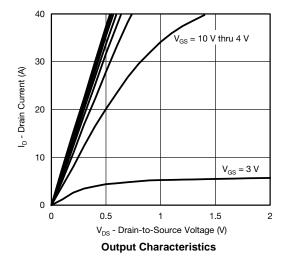
#### Notes:

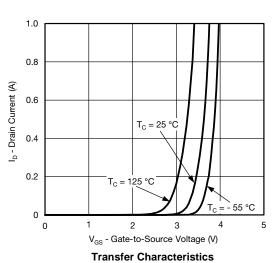
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$  b. Guaranteed by design, not subject to production testing.
- c. Independent of operating temperature.

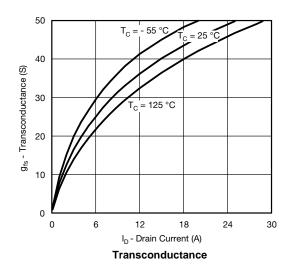
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

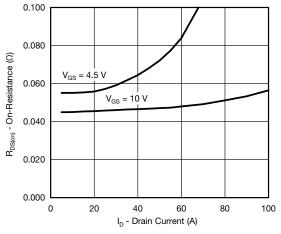


#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

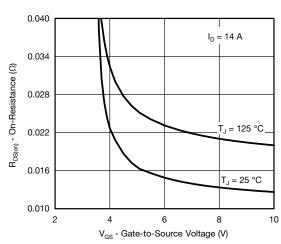




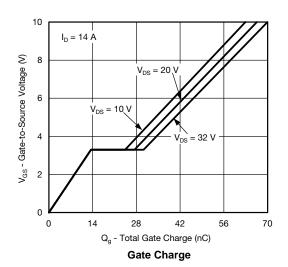




**On-Resistance vs. Drain Current** 

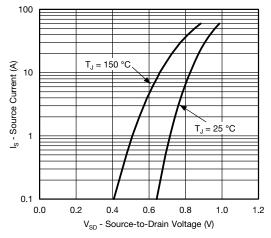


On-Resistance vs. Gate-to-Source Voltage

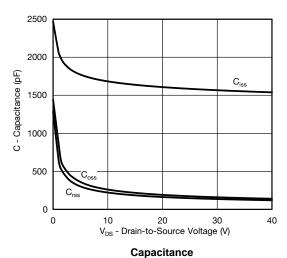




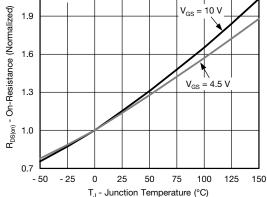
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



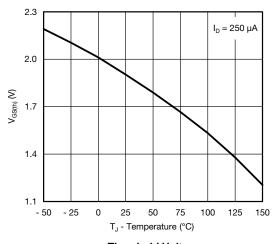
#### Source-Drain Diode Forward Voltage



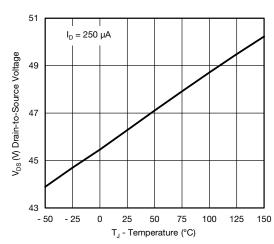
2.2 I<sub>D</sub> = 14 A 1.9



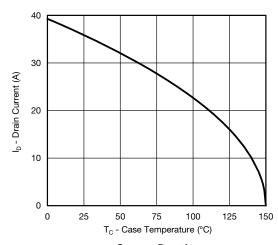
On-Resistance vs. Junction Temperature



**Threshold Voltage** 



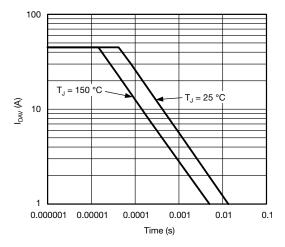
Drain Source Breakdown vs. Junction Temperature

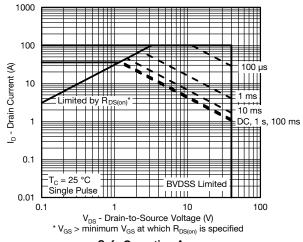


**Current Derating** 



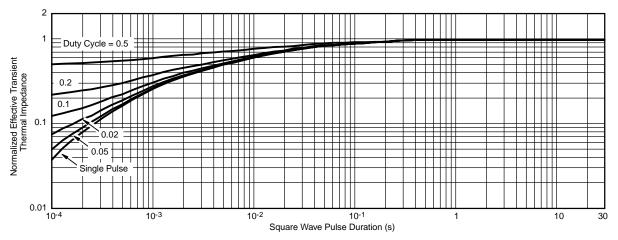
### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





Single Pulse Avalanche Current Capability vs. Time

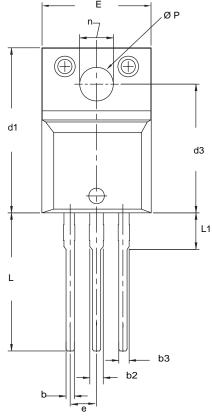


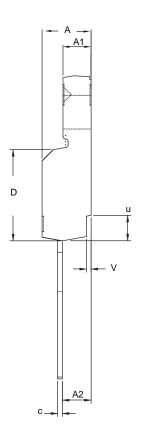


Normalized Thermal Transient Impedance, Junction-to-Case



#### **TO-220 FULLPAK (HIGH VOLTAGE)**





DIM.	MILLIMETERS		INCHES		
	MIN.	MAX.	MIN.	MAX.	
Α	4.570	4.830	0.180	0.190	
A1	2.570	2.830	0.101	0.111	
A2	2.510	2.850	0.099	0.112	
b	0.622	0.890	0.024	0.035	
b2	1.229	1.400	0.048 0		
b3	1.229	1.400	0.048		
С	0.440	0.629	0.017	0.025	
D	8.650	9.800	0.341	0.386	
d1	15.88	16.120	0.622	0.635	
d3	12.300	12.920	0.484	0.509	
E	10.360	10.630	0.408		
е	2.54	2.54 BSC		0.100 BSC	
L	13.200	13.730	0.520	0.541	
L1	3.100	3.500	0.122	0.122 0.138	
n	6.050	6.150	0.238	0.242	
ØР	3.050	3.450	0.120	0.136	
u	2.400	2.500	0.094	0.098	
V	0.400	0.500	0.016	0.020	

ECN: X09-0126-Rev. B, 26-Oct-09 DWG: 5972

- To be used only for process drawing.
   These dimensions apply to all TO-220, FULLPAK leadframe versions 3 leads.
   All critical dimensions should C meet C<sub>pk</sub> > 1.33.
- 4. All dimensions include burrs and plating thickness.
  5. No chipping or package damage.



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